

30V N-Channel MOSFET
N-Channel Enhancement Mode Power MOSFET
General Features

V_{DS}
 I_D (at $V_{GS}=10V$)
 $R_{DS(ON)}$ (at $V_{GS}=10V$)
 $R_{DS(ON)}$ (at $V_{GS}=4.5V$)

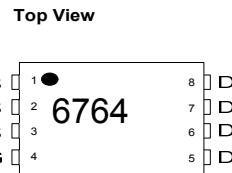
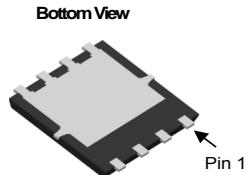
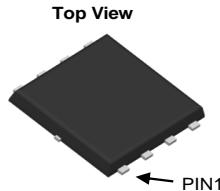
30V
85A
< 4.00mΩ
< 5.00mΩ

100% UIS Tested
100% R_g Tested

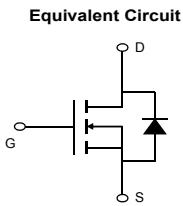
- Trench Power αMOS Technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

Applications

- DC/DC Converters in Computing
- Isolated DC/DC Converters in Telecom and Industrial

PDFN5X6-8L


Top View



Equivalent Circuit

Orderable Part Number	Package Type		Form	Minimum Order Quantity
JS6764	DFN 5x6		Tape&Reel	3000
Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted				
Parameter	Symbol	Maximum	Units	
Drain-Source Voltage	V_{DS}	30	V	
Gate-Source Voltage	V_{GS}	± 12	V	
Continuous Drain Current ^G $T_c=25^\circ C$	I_D	85	A	
Pulsed Drain Current ^C	I_{DM}	190		
Continuous Drain Current	I_{DSM}	37	A	
Avalanche Current ^C	I_{AS}	42	A	
Avalanche energy $L=0.05mH$ ^C	E_{AS}	44	mJ	
V_{DS} Spike	V_{SPIKE}	36	V	
Power Dissipation ^B	P_D	42	W	
Power Dissipation ^A	P_{DSM}	6.2	W	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C	
Thermal Characteristics				
Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		40	50	°C/W
Maximum Junction-to-Case Steady-State	$R_{\theta JC}$	2.4	3	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=10\text{mA}, \text{VGS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$			0.5	uA
I_{GSS}	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 12\text{V}$			± 100	nA
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.1	1.5	1.9	V
$\text{R}_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$		3.8	4.0	mΩ
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		4.5	5.0	mΩ
g_{FS}	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		167		S
V_{SD}	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.5	0.7	V
I_{S}	Maximum Body-Diode Continuous Current				30	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		2120		pF
C_{oss}	Output Capacitance			700		pF
C_{rss}	Reverse Transfer Capacitance			69		pF
R_{g}	Gate resistance	$\text{f}=1\text{MHz}$	0.9	1.8	2.7	Ω
SWITCHING PARAMETERS						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		37		nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			16.8		nC
Q_{gs}	Gate Source Charge			5		nC
Q_{gd}	Gate Drain Charge			4.9		nC
$\text{t}_{\text{D}(\text{on})}$	Turn-On Delay Time	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		7		ns
t_{r}	Turn-On Rise Time			3.5		ns
$\text{t}_{\text{D}(\text{off})}$	Turn-Off Delay Time			36		ns
t_{f}	Turn-Off Fall Time			6		ns
t_{rr}	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		15.5		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		33		nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\text{JJA}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$.

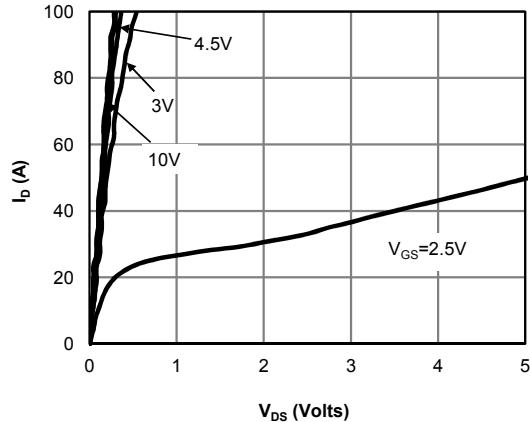
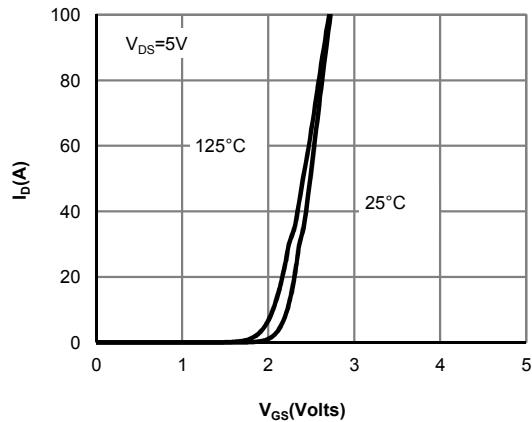
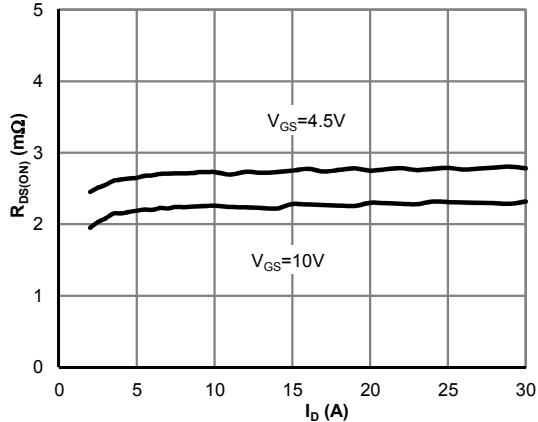
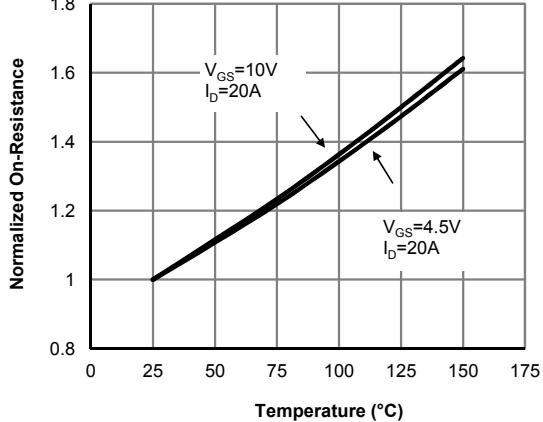
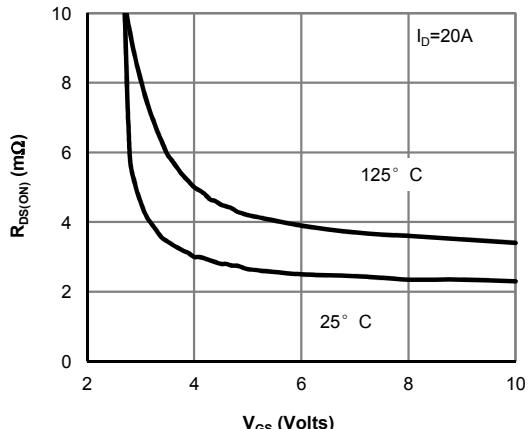
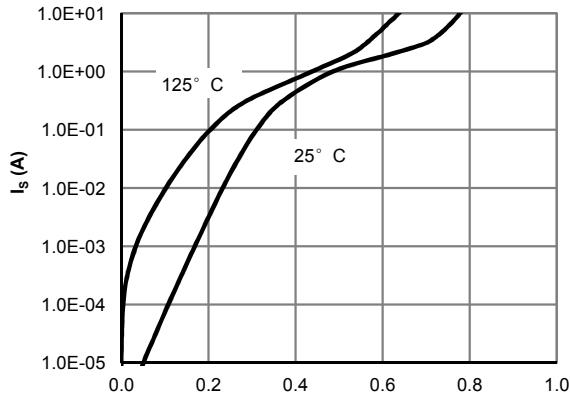
D. The R_{JJA} is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

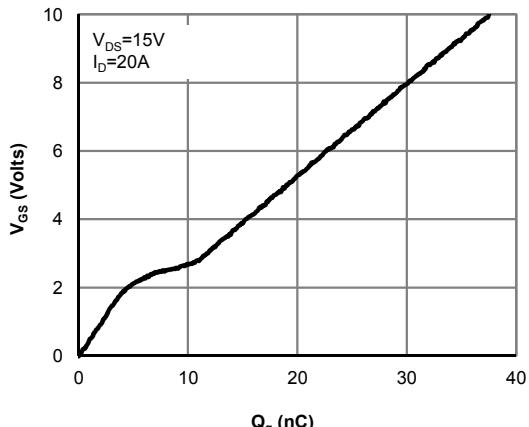
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 7: Gate-Charge Characteristics

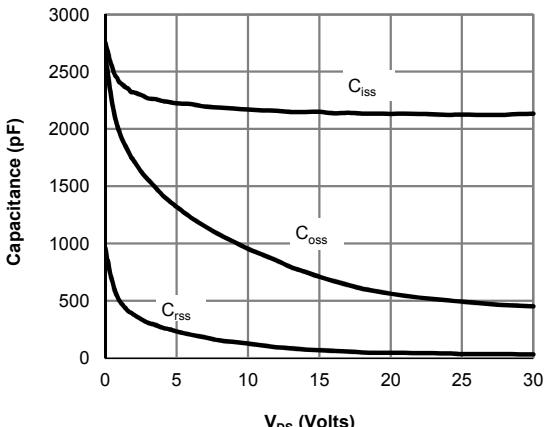


Figure 8: Capacitance Characteristics

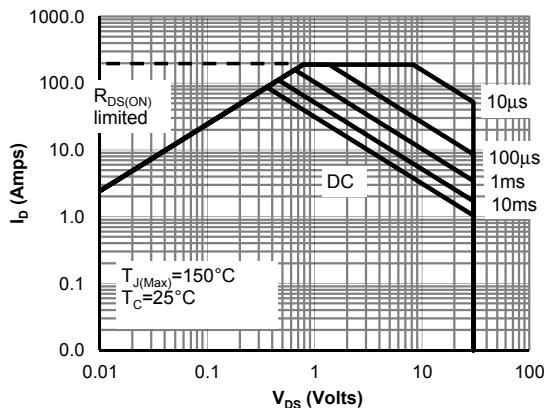


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

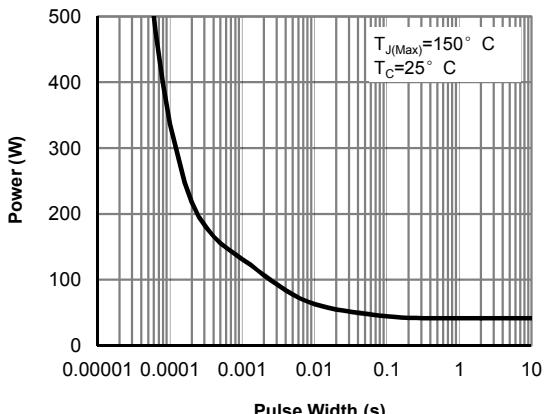


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

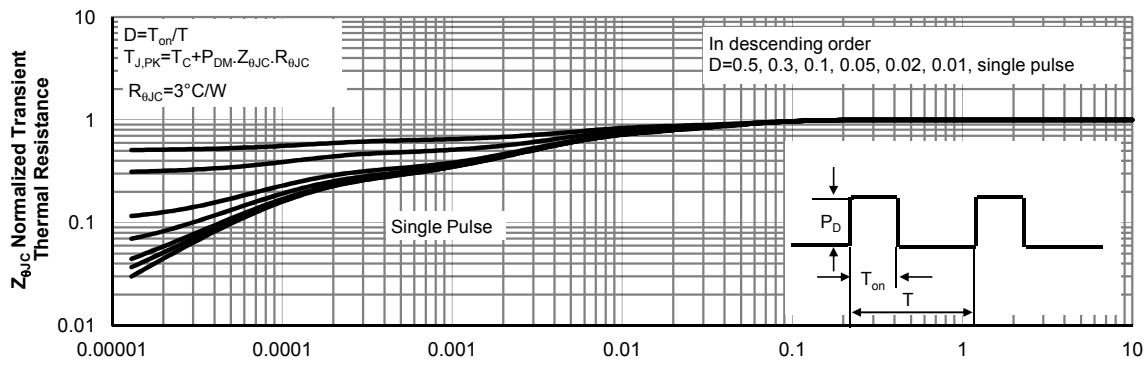


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

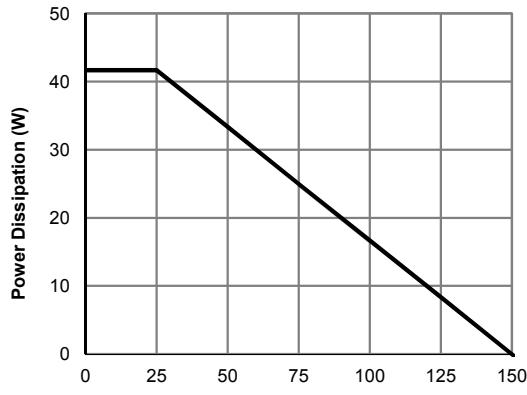
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note F)

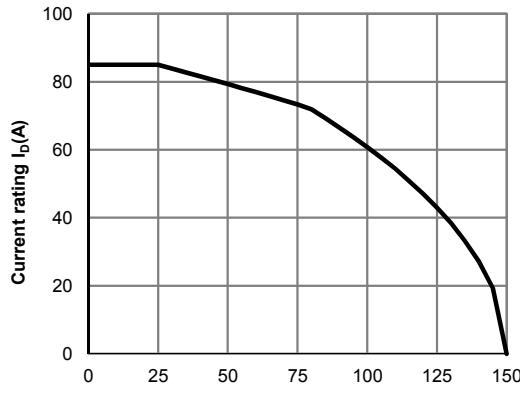


Figure 13: Current De-rating (Note F)

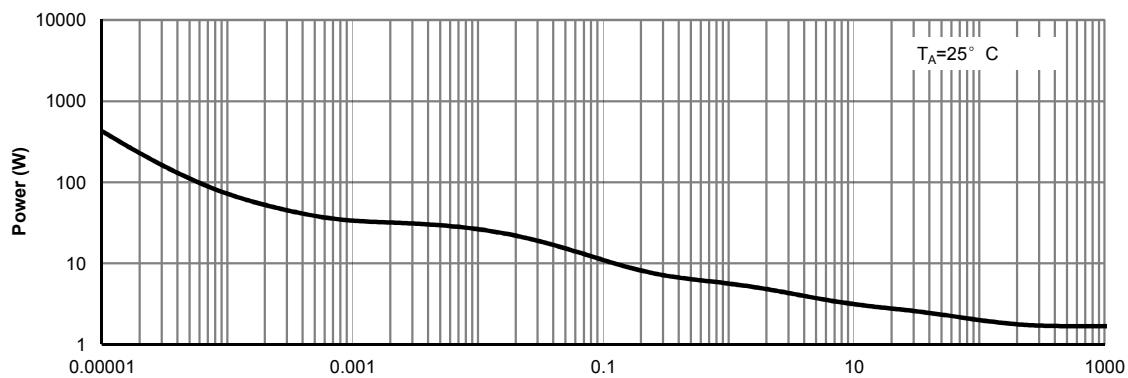


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

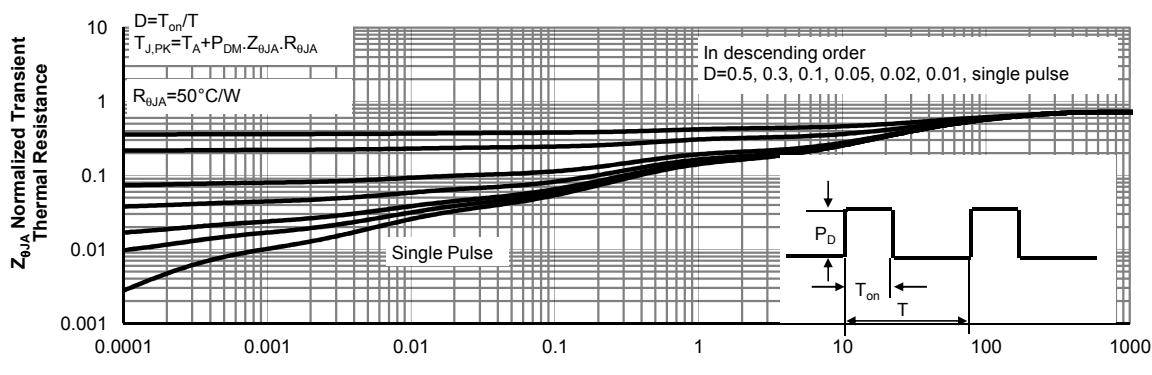
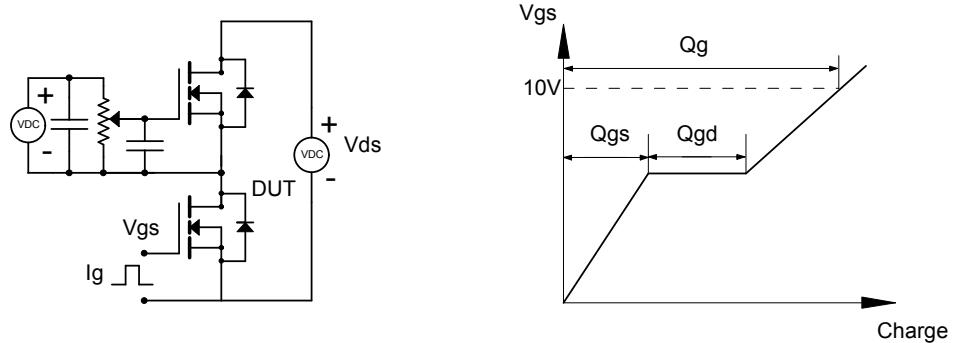
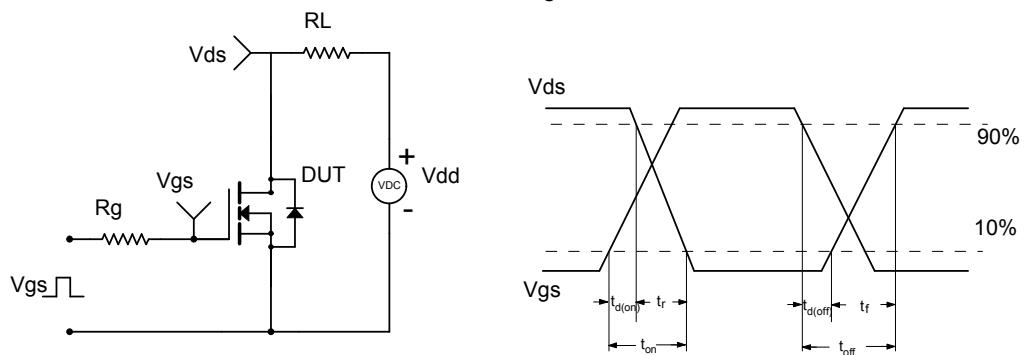
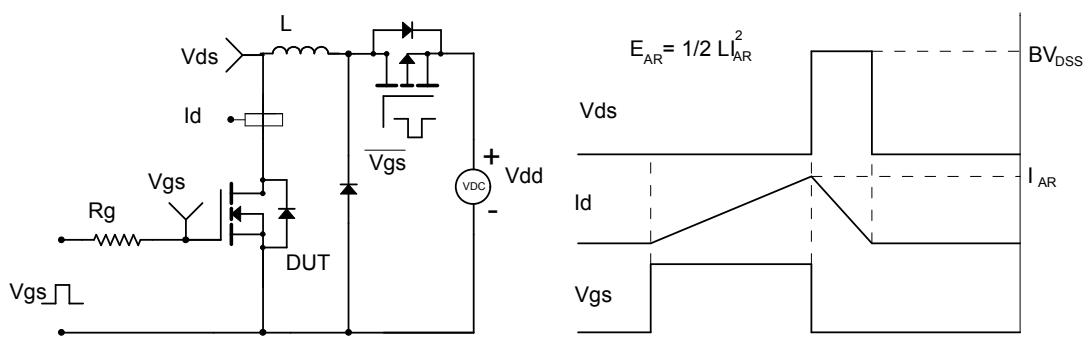
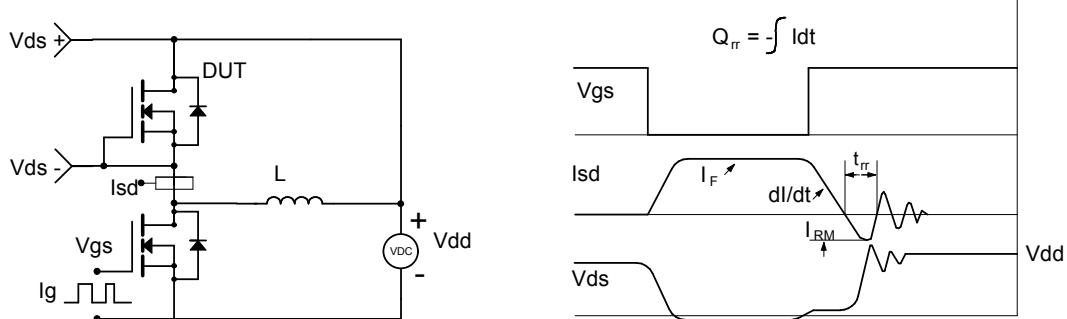
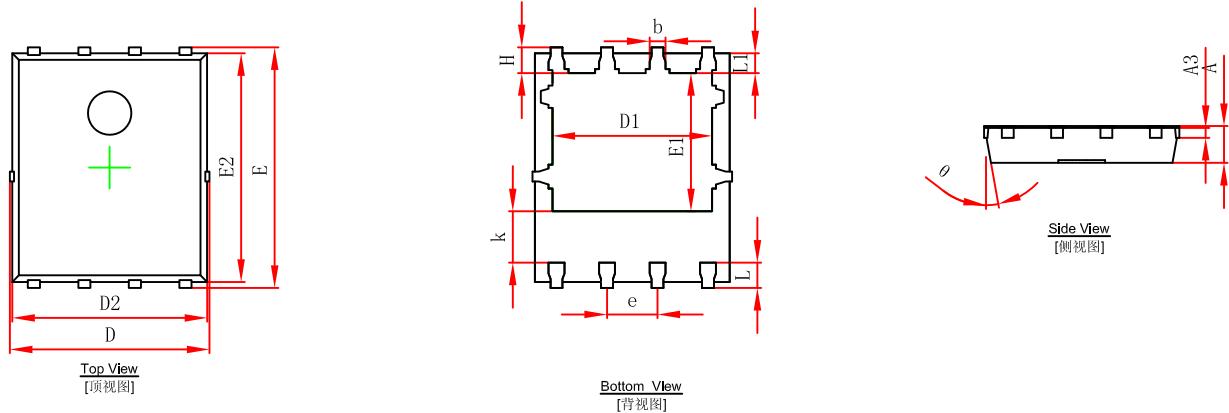


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

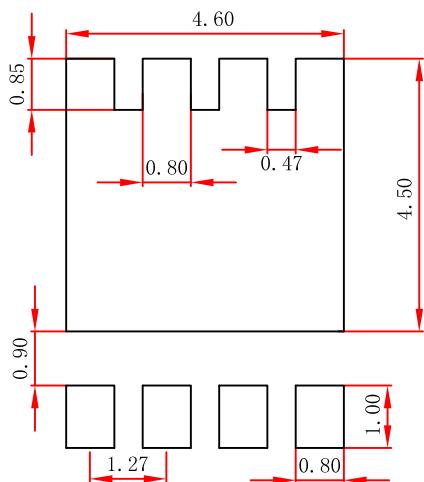
Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms


PDFNWB5x6-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

PDFNWB5x6-8L Suggested Pad Layout



Note:

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$.
3. The pad layout is for reference purposes only.